

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

General Description

The MAX3000E/MAX3001E/MAX3002–MAX3012 8-channel level translators provide the level shifting necessary to allow data transfer in a multivoltage system. Externally applied voltages, VCC and VL, set the logic levels on either side of the device. Logic signals present on the VL side of the device appear as a higher voltage logic signal on the VCC side of the device, and vice-versa.

The MAX3000E/MAX3001E/MAX3002/MAX3003 use an architecture specifically designed to be bidirectional without the use of a directional pin.

The MAX3000E/MAX3001E/MAX3002/MAX3004–MAX3012 feature an EN input that, when low, reduces the $V_{\rm CC}$ and $V_{\rm L}$ supply currents to < 2 μ A. The MAX3000E/MAX3001E also have ±15kV ESD protection on the I/O $V_{\rm CC}$ side for greater protection in applications that route signals externally. The MAX3000E operates at a guaranteed data rate of 230kbps. The MAX3001E operates at a guaranteed data rate of 4Mbps. The MAX3002–MAX3012 operate at a guaranteed data rate of 20Mbps over the entire specified operating voltage range.

The MAX3000E/MAX3001E/MAX3002–MAX3012 accept V_L voltages from +1.2V to +5.5V and V_{CC} voltages from +1.65V to +5.5V, making them ideal for data transfer between low-voltage ASICs/PLDs and higher voltage systems. The MAX3000E/MAX3001E/MAX3002–MAX3012 are available in 20-bump UCSPTM, 20-pin TQFN (5mm x 5mm), and 20-pin TSSOP packages.

_Applications

CMOS Logic-Level Translation

Cellphones

SPI™ and MICROWIRE™ Level Translation

Low-Voltage ASIC Level Translation

Smart Card Readers

Cellphone Cradles

Portable POS Systems

Portable Communication Devices

Low-Cost Serial Interfaces

GPS

Telecommunications Equipment

UCSP is a trademark of Maxim Integrated Products, Inc. SPI is a trademark of Motorola, Inc.

MICROWIRE is a trademark of National Semiconductor.

Features

- Guaranteed Data Rate Options 230kbps (MAX3000E) 4Mbps (MAX3001E) 20Mbps (MAX3002–MAX3012)
- ♦ Bidirectional Level Translation Without Using a Directional Pin (MAX3000E/MAX3001E/MAX3002/ MAX3003)
- Unidirectional Level Translation (MAX3004–MAX3012)
- ♦ Operation Down to +1.2V on V_L
- ◆ ±15kV ESD Protection on I/O V_{CC} Lines (MAX3000E/MAX3001E)
- ♦ Ultra-Low 0.1µA Supply Current in Shutdown
- ♦ Low Quiescent Current (< 10μA)
- ♦ UCSP, TQFN, and TSSOP Packages

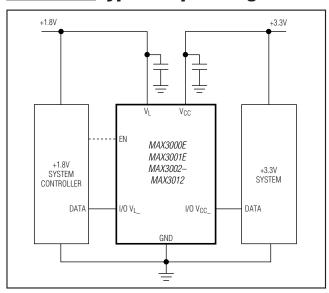
Ordering Information

| PART | TEMP RANGE | PIN-PACKAGE |
|---------------|----------------|-------------|
| MAX3000EEUP | -40°C to +85°C | 20 TSSOP |
| MAX3000EEBP-T | -40°C to +85°C | 4 x 5 UCSP |

Ordering Information continued at end of data sheet.

Note: All devices operate over the -40°C to +85°C operating temperature range.

Typical Operating Circuit



Pin Configurations and Functional Diagrams appear at end of data sheet.

For pricing, delivery, and ordering information, please contact Maxim Direct at 1-888-629-4642, or visit Maxim's website at www.maximintegrated.com.

$\pm 1.2V$ to $\pm 5.5V$, $\pm 15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

ABSOLUTE MAXIMUM RATINGS

| (All voltages referenced to GND.) |
|--|
| V _C C0.3V to +6V |
| -0.3V to +6V |
| I/O V _{CC} |
| $I/O V_L$ 0.3V to $(V_L + 0.3V)$ |
| EN, EN A/B0.3V to +6V |
| Short-Circuit Duration I/O V _L , I/O V _{CC} to GNDContinuous |
| Continuous Power Dissipation ($T_A = +70$ °C) |
| 20-Pin TSSOP (derate 7.0mW/°C above +70°C)559mW |
| 20-Bump UCSP (derate 10mW/°C above +70°C)800mW |
| 20-Pin 5mm x 5mm TQFN |
| (derate 20.0mW/°C above +70°C)1667mW |

| Operating Temperature Range | es |
|------------------------------|----------------|
| MAX3001EAUP | 40°C to +125°C |
| MAX300_EE_P | 40°C to +85°C |
| MAX30E_P | 40°C to +85°C |
| Junction Temperature | +150°C |
| Storage Temperature Range | 65°C to +150°C |
| Lead Temperature (soldering, | 10s)+300°C |
| | |

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

 $(V_{CC}=+1.65V\ to\ +5.5V,\ V_L=+1.2V\ to\ V_{CC},\ EN=V_L\ (MAX3000E/MAX3001E/MAX3002/MAX3004-MAX3012),\ EN\ A/B=V_L\ or\ 0\ (MAX3003),\ T_A=T_{MIN}\ to\ T_{MAX}.\ Typical\ values\ are\ at\ V_{CC}=+1.65V,\ V_L=+1.2V,\ and\ T_A=+25^{\circ}C.)\ (Notes\ 1,\ 2)$

| PARAMETER | PARAMETER SYMBOL CONDITIONS | | MIN | TYP | MAX | UNITS | |
|---|-----------------------------|---|------|-----|------|-------|--|
| POWER SUPPLIES | | | | | | | |
| V _L Supply Range | VL | | 1.2 | | Vcc | V | |
| V _{CC} Supply Range | Vcc | | 1.65 | | 5.50 | V | |
| Supply Current from VCC | lovoo | I/O V _{CC} _ = 0, I/O V _L _ = 0 or I/O V _{CC} _ = V _{CC} , I/O V _L _ = V _L , MAX3000E/MAX3002–MAX3012 | | 0.1 | 10 | шЛ | |
| Supply Current norm vcc | lavec | $\label{eq:VCC} \begin{split} & \text{I/O V}_{CC_} = 0, \text{I/O V}_{L_} = 0 \\ & \text{or I/O V}_{CC_} = \text{V}_{CC}, \text{I/O V}_{L_} = \text{V}_{L}, \\ & \text{MAX3001E} \end{split}$ | | 0.1 | 50 | μΑ | |
| Supply Current from V | lova | I/O V _{CC} _= 0, I/O V _L _= 0 or I/O V _{CC} _= V _{CC} , I/O V _L _= V _L , MAX3000E/MAX3002–MAX3012 | | 0.1 | 10 | | |
| Supply Current from V _L | I _{QVL} | I/O V _{CC} _= 0, I/O V _L _= 0 or I/O V _{CC} _= V _{CC} , I/O V _L _= V _L , MAX3001E | | 0.1 | 50 | μΑ | |
| V _{CC} Shutdown Supply Current | Ishdn-vcc | T _A = +25°C, EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012 | | 0.1 | 2 | μA | |
| | | T _A = +25°C, EN A/B = 0, MAX3003 | | 0.1 | 2 | | |
| V _L Shutdown Supply Current | ISHDN-VL | T _A = +25°C, EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004-MAX3012 | | 0.1 | 2 | μА | |
| | | T _A = +25°C, EN A/B = 0, MAX3003 | | 0.1 | 2 | | |

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ELECTRICAL CHARACTERISTICS (continued)

 $(V_{CC} = +1.65 V \ to \ +5.5 V, \ V_{L} = +1.2 V \ to \ V_{CC}, \ EN = V_{L} \ (MAX3000 E/MAX3001 E/MAX3002/MAX3004 - MAX3012), \ EN \ A/B = V_{L} \ or \ 0 \ (MAX3003), \ T_{A} = T_{MIN} \ to \ T_{MAX}. \ Typical \ values \ are \ at \ V_{CC} = +1.65 V, \ V_{L} = +1.2 V, \ and \ T_{A} = +25 ^{\circ}C.) \ (Notes \ 1, \ 2)$

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
|---|------------------|--|-----------------------|-----|-----------------------|-------|
| I/O V _{CC} _ Three-State Output Leakage Current | | T _A = +25°C, EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012 | | 0.1 | 2 | μΑ |
| Leanage Guirent | | T _A = +25°C, EN A/B = 0, MAX3003 | | 0.1 | 2 | |
| I/O V _L Three-State Output Leakage Current | | EN A/B = 0, MAX3003 | | 0.1 | 2 | μΑ |
| I/O V _L _Pulldown Resistance During Shutdown | | EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012 | 4.59 | | 8.30 | kΩ |
| EN or EN A/B Input Leakage Current | | T _A = +25°C | | | 1 | μΑ |
| LOGIC-LEVEL THRESHOLDS | | | | | | |
| I/O V _L Input-Voltage High Threshold | VIHL | | | | 2/3 x V _L | V |
| I/O V _L Input-Voltage Low Threshold | VILL | | 1/3 x V _L | | | V |
| I/O V _{CC} _ Input-Voltage High Threshold | VIHC | | | | 2/3 x V _{CC} | V |
| I/O V _{CC} _ Input-Voltage Low Threshold | V _{ILC} | | 1/3 x V _{CC} | | | V |
| EN, EN A/B Input-Voltage High Threshold | VIH | | | | V _L - 0.4 | V |
| EN, EN A/B Input-Voltage Low Threshold | VIL | | 0.4 | | | V |
| I/O V _L _ Output-Voltage High | Vohl | I/O V _L source current = 20µA, I/O V _{CC} ≥ V _{CC} - 0.4V | V _L - 0.4 | | | V |
| I/O V _L Output-Voltage Low | Voll | I/O V _L _ sink current = 20µA, I/O V _{CC} _ ≤ 0.4V | | | 0.4 | V |
| I/O V _{CC} _ Output-Voltage High | Vohc | I/O V _{CC} source current = 20μ A, I/O V _L \geq V _L - 0.4 V | V _{CC} - 0.4 | | | V |
| I/O V _{CC} _ Output-Voltage Low | Volc | I/O V _{CC} sink current = 20µA, I/O V _L ≤ 0.4V | | | 0.4 | V |
| ESD PROTECTION | | | | | | |
| I/O V _{CC} _ | | Human Body Model, MAX3000E/MAX3001E | | ±15 | | kV |

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TIMING CHARACTERISTICS

 $(V_{CC} = +1.65V \text{ to } +5.5V, V_L = +1.2V \text{ to } V_{CC}, EN = V_L \text{ (MAX3000E/MAX3001E/MAX3002/MAX3004-MAX3012)}, EN A/B = V_L \text{ or 0 (MAX3003)}, T_A = T_{MIN} \text{ to T}_{MAX}. Typical values are at V}_{CC} = +1.65V, V_L = +1.2V, \text{ and T}_{A} = +25^{\circ}C.) \text{ (Notes 1, 2)}$

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | |
|--|-----------------------|---|-----|-----|------|-------|--|
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3000E, Figures 1a, 1b | 400 | 800 | 1200 | | |
| I/O V _{CC} _ Rise Time | tRVCC | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3001E, Figures 1a, 1b | | 25 | 50 | ns | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50pF$, MAX3002–MAX3012, Figures 1a, 1b | | | 15 | | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3000E, Figures 1a, 1b | 400 | 800 | 1200 | | |
| I/O V _{CC} _ Fall Time | tFVCC | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3001E, Figures 1a, 1b | | 25 | 50 | ns | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50pF$, MAX3002–MAX3012, Figures 1a, 1b | | | 15 | | |
| | | $R_S = 50\Omega$, $C_{VL} = 50pF$, MAX3000E, Figures 2a, 2b | 400 | 800 | 1200 | | |
| I/O VL_ Rise Time | t _{RVL} | $R_S = 50\Omega$, $C_{VL} = 50pF$, MAX3001E, Figures 2a, 2b | | 25 | 50 | ns | |
| | | $R_S = 50\Omega$, $C_{VL} = 15pF$, MAX3002–MAX3012, Figures 2a, 2b | | | 15 | | |
| | tFVL | $R_S = 50\Omega$, $C_{VL} = 50pF$, MAX3000E, Figures 2a, 2b | 400 | 800 | 1200 | | |
| I/O VL_ Fall Time | | $R_S = 50\Omega$, $C_{VL} = 50pF$, MAX3001E, Figures 2a, 2b | | 25 | 65 | ns | |
| | | $R_S = 50\Omega$, $C_{VL} = 15pF$, MAX3002–MAX3012, Figures 2a, 2b | | | 15 | | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3000E, Figures 1a, 1b | | | 1000 | | |
| Propagation Delay (Driving I/O VL_) | I/O _{VL-VCC} | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3001E, Figures 1a, 1b | | | 50 | ns | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50pF$, MAX3002–MAX3012, Figures 1a, 1b | | | 20 | | |
| | | $R_S = 50\Omega$, $C_{VL} = 50pF$, MAX3000E, Figures 2a, 2b | | | 1000 | ns | |
| Propagation Delay (Driving I/O V _{CC} _) | I/Ovcc-vl | $R_S = 50\Omega$, $C_{VL} = 50pF$, MAX3001E, Figures 2a, 2b | | | 50 | | |
| | | $R_S = 50\Omega$, $C_{VL} = 15pF$, MAX3002–MAX3012, Figures 2a, 2b | | | 20 | | |

Note 1: All units are 100% production tested at $T_A = +25$ °C. Limits over the operating temperature range are guaranteed by design and not production tested.

Note 2: For normal operation, ensure that $V_L < V_{CC}$. During power-up, $V_L > V_{CC}$ does not damage the device.

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TIMING CHARACTERISTICS (continued)

 $(V_{CC} = +1.65 V \text{ to } +5.5 V, \ V_L = +1.2 V \text{ to } V_{CC}, \ EN = V_L \ (MAX3000 E/MAX3001 E/MAX3002/MAX3004 - MAX3012), \ EN \ A/B = V_L \ or \ 0 \ (MAX3003), \ T_A = T_{MIN} \ to \ T_{MAX}. \ Typical \ values \ are \ at \ V_{CC} = +1.65 V, \ V_L = +1.2 V, \ and \ T_A = +25 °C.) \ (Notes 1, 2)$

| PARAMETER | PARAMETER SYMBOL CONDITIONS | | MIN | TYP | MAX | UNITS |
|---|-----------------------------|---|-----|-----|------|-------|
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3000E | | | 500 | |
| Channel-to-Channel Skew | tskew | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3001E | | | 10 | ns |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 15$ pF, MAX3002–MAX3012 | | | 5 | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, $\Delta T_A = +20$ °C, MAX3000E (Note 3) | | | 800 | |
| Part-to-Part Skew | tppskew | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, $\Delta T_A = +20$ °C, MAX3001E (Note 3) | | | 30 | ns |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 15$ pF, $\Delta T_A = +20$ °C, MAX3002–MAX3012 (Note 3) | | | 10 | |
| Propagation Delay from I/O V _L to I/O V _{CC} after EN | tEN-VCC | C _{VCC} = 50pF, MAX3000E/MAX3001E, MAX3002–MAX3012, Figure 3 | | | 2 | μs |
| Propagation Delay from I/O V _{CC} to I/O V _L after EN | t _{EN-VL} | C _{VL} = 50pF, MAX3000E/MAX3001E/ MAX3002/MAX3004–MAX3012, Figure 4 | | | 2 | μs |
| I/O VCC_ to I/O VC_ after EIV | | C _{VL} = 15pF, MAX3003, Figure 4 | 2 | | 2 | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3000E | 230 | | | kbps |
| Maximum Data Rate | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3001E | 4 | | Mbps | |
| | | $R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 15$ pF, MAX3002–MAX3012 | 20 | | | Mbps |

Note 3: V_{CC} from device 1 must equal V_{CC} of device 2; V_L from device 1 must equal V_L of device 2.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

TIMING CHARACTERISTICS—MAX3002-MAX3012

 $(V_{CC} = +1.65V \text{ to } +5.5V, V_L = +1.2V \text{ to } V_{CC}, EN = V_L \text{ (MAX3002/MAX3004-MAX3012)}, EN A/B = V_L \text{ or 0 (MAX3003)}, T_A = T_{MIN} \text{ to } T_{MAX.})$ (Notes 1, 2)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | |
|---|-----------------------|--------------------------------|-----|-----|-----|-------|--|
| $+1.2V \leq V_L \leq V_{CC} \leq +3.3V$ | • | | • | | | | |
| I/O V _{CC} _ Rise Time | t _{RVCC} | | | | 15 | ns | |
| I/O V _{CC} _ Fall Time | tFVCC | | | | 15 | ns | |
| I/O V _L _ Rise Time | t _{RVL} | | | | 15 | ns | |
| I/O V _L _ Fall Time | t _{FVL} | | | | 15 | ns | |
| Propagation Delay | I/O _{VL-VCC} | Driving I/O V _L _ | | | 15 | 20 | |
| Propagation Delay | I/Ovcc-vl | Driving I/O V _{CC} _ | | | 15 | ns | |
| Channel-to-Channel Skew | tskew | Each translator equally loaded | | | 5 | ns | |
| Maximum Data Rate | | | 20 | | | Mbps | |
| +2.5V ≤ V _L ≤ V _{CC} ≤ +3.3V | | | | | | | |
| I/O V _{CC} _ Rise Time | tRVCC | | | | 8.5 | ns | |
| I/O V _{CC} _ Fall Time | tFVCC | | | | 8.5 | ns | |
| I/O V _L _ Rise Time | t _{RVL} | | | | 8.5 | ns | |
| I/O V _L _ Fall Time | t _{FVL} | | | | 8.5 | ns | |
| Dropogation Dolov | I/O _{VL-VCC} | Driving I/O V _L _ | | | 8.5 | | |
| Propagation Delay | I/O _{VCC-VL} | Driving I/O V _{CC} _ | | | 8.5 | ns | |
| Channel-to-Channel Skew | tskew | Each translator equally loaded | | | 10 | ns | |
| Maximum Data Rate | | | 35 | | | Mbps | |
| $\textbf{+1.8V} \leq \textbf{V}_{\textbf{L}} \leq \textbf{V}_{\textbf{CC}} \leq \textbf{+2.5V}$ | | | | | | | |
| I/O V _{CC} _ Rise Time | tRVCC | | | | 10 | ns | |
| I/O V _{CC} _ Fall Time | tFVCC | | | | 10 | ns | |
| I/O V _{L_} Rise Time | t _{RVL} | | | | 10 | ns | |
| I/O V _L _ Fall Time | t _{FVL} | | | | 10 | ns | |
| Duran and the Delay | I/O _{VL-VCC} | Driving I/O V _L _ | | | 15 | | |
| Propagation Delay | I/O _{VCC-VL} | Driving I/O V _{CC} _ | | | 10 | ns | |
| Channel-to-Channel Skew | tskew | Each translator equally loaded | | | 5 | ns | |
| Maximum Data Rate | | | 30 | | | Mbps | |

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

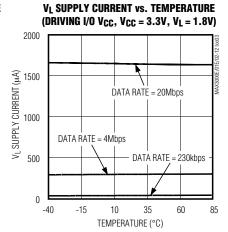
Typical Operating Characteristics

 $(T_A = +25^{\circ}C, \text{ unless otherwise noted.})$

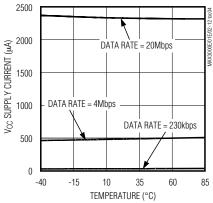
V_L SUPPLY CURRENT vs. SUPPLY VOLTAGE (DRIVING I/O V_L, V_L = 1.8V)

OUT 1.5 2.0 2.5 3.0 3.5 4.0 4.5 5.0 5.5 SUPPLY VOLTAGE (V)

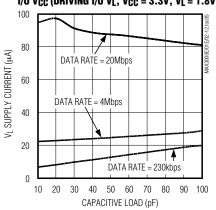
Voc SUPPLY CURRENT vs. SUPPLY VOLTAGE (DRIVING I/O V_L , $V_L = 1.8V$) 10,000 DATA RATE = 20Mbps 8000 V_{CC} SUPPLY CURRENT (μA) 6000 DATA RATE = 4Mbps 4000 DATA RATE = 230kbps 2000 n 2.0 2.5 3.0 3.5 4.0 4.5 5.0 SUPPLY VOLTAGE (V)



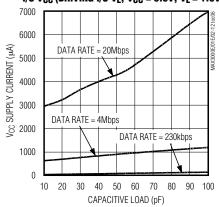
 v_{CC} supply current vs. Temperature (Driving I/O $v_{CC},\,v_{CC}=3.3v,\,v_{L}=1.8v)$



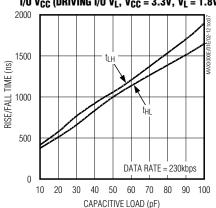
 V_L SUPPLY CURRENT vs. CAPACITIVE LOAD ON I/O V_{CC} (DRIVING I/O V_L , V_{CC} = 3.3V, V_L = 1.8V)



 V_{CC} Supply current vs. capacitive load on I/O V_{CC} (driving I/O V_L , V_{CC} = 3.3V, V_L = 1.8V)



 $\label{eq:max3000E} \begin{array}{c} \text{Max3000E} \\ \text{Rise/fall time vs. Capacitive load on} \\ \text{I/O V}_{CC} \ (\text{Driving I/O V}_L, \, \text{V}_{CC} = 3.3\text{V}, \, \text{V}_L = 1.8\text{V}) \end{array}$

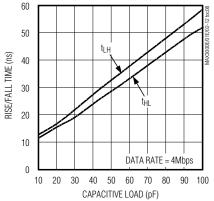


+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

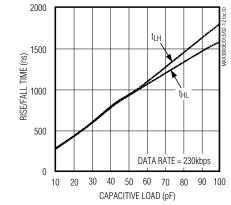
Typical Operating Characteristics (continued)

 $(T_A = +25^{\circ}C, \text{ unless otherwise noted.})$

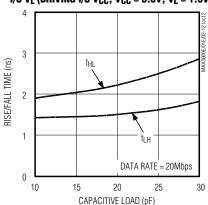
 $\label{eq:max3001E} \begin{array}{c} \text{Max3001E} \\ \text{Rise/fall time vs. Capacitive load on} \\ \text{I/O V}_{CC} \ (\text{Driving I/O V}_L, \ \text{V}_{CC} = 3.3V, \ \text{V}_L = 1.8V) \end{array}$



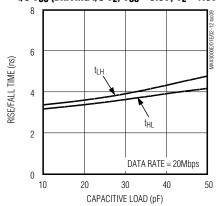
 $\label{eq:max3000E} \begin{array}{c} \text{Max3000E} \\ \text{Rise/fall time vs. Capacitive load on} \\ \text{I/O V}_L \text{ (Driving I/O V}_{CC}, \text{V}_{CC} = 3.3\text{V}, \text{V}_L = 1.8\text{V}) \end{array}$



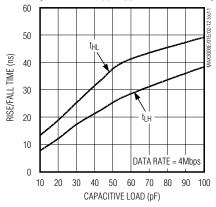
 $\label{eq:max3002-max3012} \begin{aligned} &\text{Max3002-max3012} \\ &\text{Rise/Fall Time vs. Capacitive load on} \\ &\text{I/O VL (Driving I/O VCC, VCC = 3.3V, VL = 1.8V)} \end{aligned}$



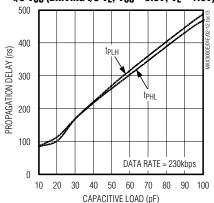
 $\label{eq:max3002-max3012} \begin{aligned} &\text{Max3002-max3012}\\ &\text{Rise/fall time vs. Capacitive load on}\\ &\text{I/O V}_{CC} \ (\text{Driving I/O V}_{L}, \, \text{V}_{CC} = 3.3\text{V}, \, \text{V}_{L} = 1.8\text{V}) \end{aligned}$



 $\label{eq:max3001E} \begin{array}{c} \text{Max3001E} \\ \text{RISE/FALL TIME vs. CAPACITIVE LOAD ON} \\ \text{I/O VL (DRIVING I/O VCC, VCC = 3.3V, VL = 1.8V)} \end{array}$



 $\label{eq:max3000E} MAX3000E \\ PROPAGATION DELAY vs. CAPACITIVE LOAD ON \\ I/O \ V_{CC} \ (DRIVING I/O \ V_L, \ V_{CC} = 3.3V, \ V_L = 1.8V) \\$

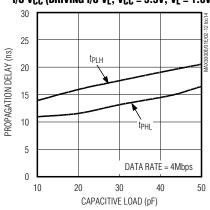


+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

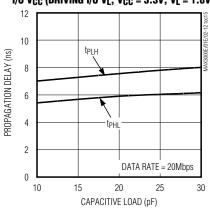
Typical Operating Characteristics (continued)

 $(T_A = +25$ °C, unless otherwise noted.)

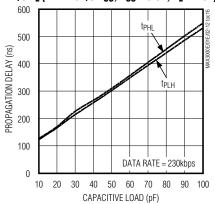
 $\begin{array}{c} \text{MAX3001E} \\ \text{PROPAGATION DELAY vs. CAPACITIVE LOAD ON} \\ \text{I/O V}_{CC} \left(\text{DRIVING I/O V}_{L}, \text{V}_{CC} = 3.3\text{V}, \text{V}_{L} = 1.8\text{V} \right) \end{array}$



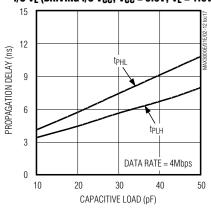
 $\label{eq:max3002-max3012} \mbox{PROPAGATION DELAY vs. CAPACITIVE LOAD ON } \mbox{I/O V}_{CC} \mbox{ (DRIVING I/O V}_{L}, \mbox{ V}_{CC} = 3.3V, \mbox{ V}_{L} = 1.8V) \mbox{}$



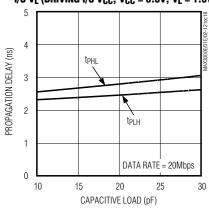
MAX3000E
PROPAGATION DELAY vs. CAPACITIVE LOAD ON I/O VL (DRIVING I/O VCC, VCC = 3.3V, VL = 1.8V)



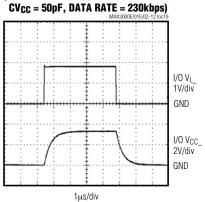
 $\begin{array}{c} MAX3001E \\ PROPAGATION DELAY vs. CAPACITIVE LOAD ON \\ I/O V_L (DRIVING I/O V_{CC}, V_{CC} = 3.3V, V_L = 1.8V) \end{array}$



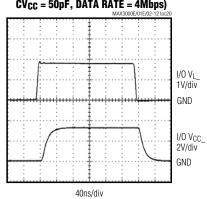
 $\label{eq:max3002-max3012} MAX3002-MAX3012 $$PROPAGATION DELAY vs. CAPACITIVE LOAD ON $$I/O V_L (DRIVING I/O V_{CC}, V_{CC} = 3.3V, V_L = 1.8V) $$$

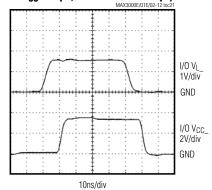


MAX3000E RAIL-TO-RAIL DRIVING
(DRIVING I/O V_L, V_{CC} = 3.3V, V_L = 1.8V,
CV_{CC} = 50pe DATA RATE = 230kbps)



MAX3001E RAIL-TO-RAIL DRIVING (DRIVING I/O V_L , $V_{CC} = 3.3V$, $V_L = 1.8V$, $CV_{CC} = 50pF$, DATA RATE = 4Mbps)





+1.2V to +5.5V, $\pm15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

Pin Description

MAX3000E/MAX3001E/MAX3002

| PIN | | NAME | FUNCTION | |
|-------|------|------|-----------------------|---|
| TSSOP | UCSP | TQFN | NAME | FUNCTION |
| 1 | B1 | 19 | I/O V _L 1 | Input/Output 1, Referenced to V _L |
| 2 | A1 | 20 | VL | Logic Input Voltage, $+1.2V \le V_L \le V_{CC}$. Bypass V_L to GND with a $0.1\mu F$ capacitor. |
| 3 | A2 | 1 | I/O VL2 | Input/Output 2, Referenced to V _L |
| 4 | B2 | 2 | I/O VL3 | Input/Output 3, Referenced to V _L |
| 5 | A3 | 3 | I/O VL4 | Input/Output 4, Referenced to V _L |
| 6 | В3 | 4 | I/O V _L 5 | Input/Output 5, Referenced to V _L |
| 7 | A4 | 5 | I/O V _L 6 | Input/Output 6, Referenced to V _L |
| 8 | B4 | 6 | I/O V _L 7 | Input/Output 7, Referenced to V _L |
| 9 | A5 | 7 | I/O VL8 | Input/Output 8, Referenced to V _L |
| 10 | B5 | 8 | EN | Enable Input. If EN is pulled low, I/O $V_{CC}1$ to I/O $V_{CC}8$ are in three-state, while I/O $V_{L}1$ to I/O $V_{L}8$ have internal $6k\Omega$ pulldown resistors. Drive EN high (V_{L}) for normal operation. |
| 11 | C5 | 9 | GND | Ground |
| 12 | D5 | 10 | I/O V _{CC} 8 | Input/Output 8, Referenced to V _{CC} |
| 13 | C4 | 11 | I/O V _{CC} 7 | Input/Output 7, Referenced to V _{CC} |
| 14 | D4 | 12 | I/O V _{CC} 6 | Input/Output 6, Referenced to V _{CC} |
| 15 | C3 | 13 | I/O Vcc5 | Input/Output 5, Referenced to VCC |
| 16 | D3 | 14 | I/O V _{CC} 4 | Input/Output 4, Referenced to V _{CC} |
| 17 | C2 | 15 | I/O V _{CC} 3 | Input/Output 3, Referenced to V _{CC} |
| 18 | D2 | 16 | I/O V _{CC} 2 | Input/Output 2, Referenced to V _{CC} |
| 19 | D1 | 17 | Vcc | V _{CC} Input Voltage, +1.65V ≤ V _{CC} ≤ +5.5V. Bypass V _{CC} to GND with a 0.1μF capacitor. |
| 20 | C1 | 18 | I/O V _{CC} 1 | Input/Output 1, Referenced to V _{CC} |
| _ | _ | EP | EP | Exposed Pad. Connect to GND. |

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1µA, 35Mbps, 8-Channel Level Translators

Pin Description (continued)

MAX3003

| PIN | | PIN | | FUNCTION | | |
|-------|------|------|------------------------|--|--|--|
| TSSOP | UCSP | TQFN | NAME | FUNCTION | | |
| 1 | B1 | 19 | I/O V _L 1A | Input/Output 1A, Referenced to V _L | | |
| 2 | A1 | 20 | VL | Logic Input Voltage, $+1.2V \le V_L \le V_{CC}$. Bypass V_L to GND with a $0.1\mu F$ capacitor. | | |
| 3 | A2 | 1 | I/O VL2A | Input/Output 2A, Referenced to V _L | | |
| 4 | B2 | 2 | I/O VL3A | Input/Output 3A, Referenced to V _L | | |
| 5 | АЗ | 3 | I/O VL4A | Input/Output 4A, Referenced to V _L | | |
| 6 | В3 | 4 | I/O V _L 1B | Input/Output 1B, Referenced to V _L | | |
| 7 | A4 | 5 | I/O VL2B | Input/Output 2B, Referenced to VL | | |
| 8 | B4 | 6 | I/O VL3B | Input/Output 3B, Referenced to V _L | | |
| 9 | A5 | 7 | I/O VL4B | Input/Output 4B, Referenced to V _L | | |
| 10 | B5 | 8 | EN A/B | Enable Input. If EN A/B is pulled low, channels 1B through 4B are active, and channels 1A through 4A are in three-state. If EN A/B is driven high to V_L , channels 1A through 4A are active, and channels 1B through 4B are in three-state. | | |
| 11 | C5 | 9 | GND | Ground | | |
| 12 | D5 | 10 | I/O V _{CC} 4B | Input/Output 4B, Referenced to VCC | | |
| 13 | C4 | 11 | I/O V _{CC} 3B | Input/Output 3B, Referenced to V _{CC} | | |
| 14 | D4 | 12 | I/O V _{CC} 2B | Input/Output 2B, Referenced to VCC | | |
| 15 | C3 | 13 | I/O V _{CC} 1B | Input/Output 1B, Referenced to V _{CC} | | |
| 16 | D3 | 14 | I/O V _{CC} 4A | Input/Output 4A, Referenced to V _{CC} | | |
| 17 | C2 | 15 | I/O V _{CC} 3A | Input/Output 3A, Referenced to VCC | | |
| 18 | D2 | 16 | I/O V _{CC} 2A | Input/Output 2A, Referenced to V _{CC} | | |
| 19 | D1 | 17 | Vcc | V _{CC} Input Voltage, +1.65V ≤ V _{CC} ≤ +5.5V. Bypass V _{CC} to GND with a 0.1µF capacitor. | | |
| 20 | C1 | 18 | I/O V _{CC} 1A | Input/Output 1A, Referenced to VCC | | |
| _ | _ | EP | EP | Exposed Pad. Connect to GND. | | |

$\pm 1.2 V$ to $\pm 5.5 V$, $\pm 15 kV$ ESD-Protected, $0.1 \mu A$, 35Mbps, 8-Channel Level Translators

Pin Description (continued)

MAX3004-MAX3012

| NAME | FUNCTION (Note 1) |
|---------------------------------------|---|
| Vcc | V _{CC} Input Voltage, +1.65V < V _{CC} < +5.5V. Bypass V _{CC} to GND with a 0.1µF capacitor. |
| VL | Logic Input Voltage, $+1.2V \le V_L \le V_{CC}$. Bypass V_L to GND with a $0.1\mu F$ capacitor. |
| GND | Ground |
| EN (MAX3004) | Enable Input. If EN is pulled low, OV _{CC} 1–OV _{CC} 8 are in three-state, while IV _L 1–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3005) | Enable Input. If EN is pulled low, IV _{CC} 1 and OV _{CC} 2–OV _{CC} 8 are in three-state, while OV _L 1 and IV _L 2–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3006) | Enable Input. If EN is pulled low, IV _{CC} 1, IV _{CC} 2, and OV _{CC} 3–OV _{CC} 8 are in three-state, while OV _L 1, OV _L 2, and IV _L 3–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3007) | Enable Input. If EN is pulled low, IV _{CC} 1, IV _{CC} 2, IV _{CC} 3, and OV _{CC} 4–OV _{CC} 8 are in three-state, while OV _L 1, OV _L 2, OV _L 3, and IV _L 4–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3008) | Enable Input. If EN is pulled low, IV _{CC} 1–IV _{CC} 4 and OV _{CC} 5–OV _{CC} 8 are in three-state, while OV _L 1–OV _L 4 and IV _L 5–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3009) | Enable Input. If EN is pulled low, IV _{CC} 1–IV _{CC} 5, OV _{CC} 6, OV _{CC} 7, and OV _{CC} 8 are in three-state, while OV _L 1–OV _L 5, IV _L 6, IV _L 7, and IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3010) | Enable Input. If EN is pulled low, IV _{CC} 1–IV _{CC} 6, OV _{CC} 7, and OV _{CC} 8 are in three-state, while OV _L 1–OV _L 6, IV _L 7, and IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3011) | Enable Input. If EN is pulled low, IV _{CC} 1–IV _{CC} 7 and OV _{CC} 8 are in three-state, while OV _L 1–OV _L 7 and IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| EN (MAX3012) | Enable Input. If EN is pulled low, IV _{CC} 1–IV _{CC} 8 are in three-state, while OV _L 1–OV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation. |
| IV _L 1–IV _L 8 | Inputs Referenced to V _L , Numbers 1 to 8 |
| OV _L 1–OV _L 8 | Outputs Referenced to V _L , Numbers 1 to 8 |
| IV _{CC} 1-IV _{CC} 8 | Inputs Referenced to V _{CC} , Numbers 1 to 8 |
| OV _{CC} 1-OV _{CC} 8 | Outputs Referenced to V _{CC} , Numbers 1 to 8 |

Note 1: For specific pin numbers, see the Pin Configurations.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Test Circuits/Timing Diagrams

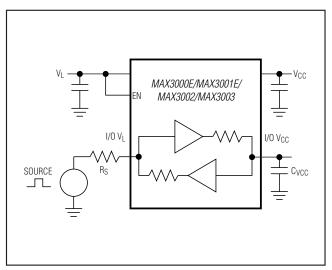


Figure 1a. Driving I/O VL

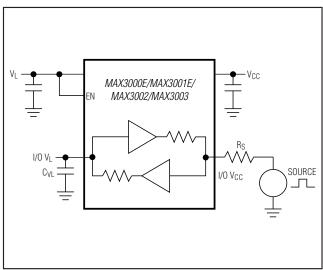


Figure 2a. Driving I/O VCC

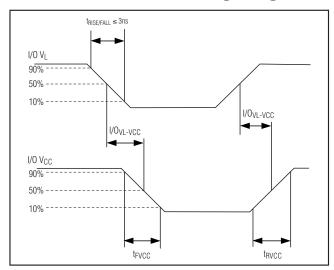


Figure 1b. Timing for Driving I/O VL

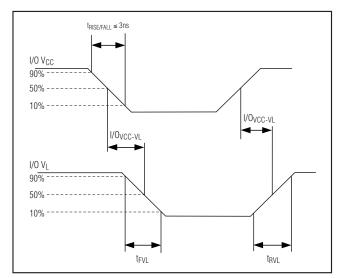


Figure 2b. Timing for Driving I/O VCC

+1.2V to +5.5V, $\pm15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

Test Circuits/Timing Diagrams (continued)

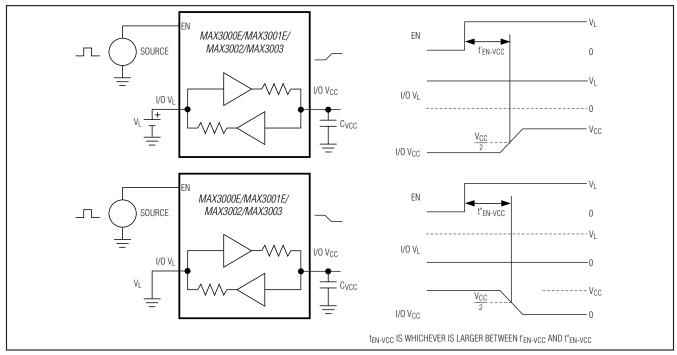


Figure 3. Propagation Delay from I/O V_L to I/O V_{CC} After EN

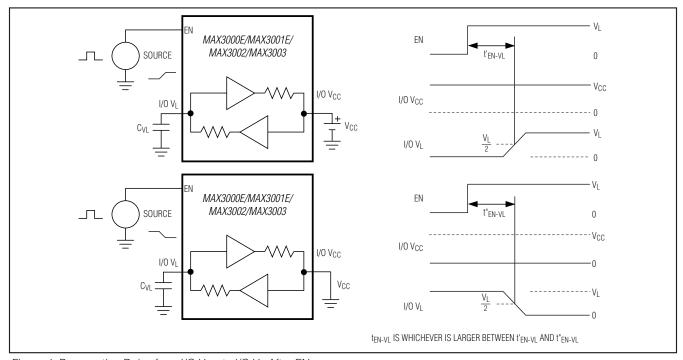


Figure 4. Propagation Delay from I/O V_{CC} to I/O V_L After EN

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Detailed Description

The MAX3000E/MAX3001E/MAX3002-MAX3012 logiclevel translators provide the level shifting necessary to allow data transfer in a multivoltage system. Externally applied voltages, VCC and VL, set the logic levels on either side of the device. Logic signals present on the V₁ side of the device appear as a higher voltage logic signal on the Vcc side of the device, and vice-versa. The MAX3000E/MAX3001E/MAX3002/MAX3003 are bidirectional level translators allowing data translation in either direction (V_L ↔ V_{CC}) on any single data line. These devices use an architecture specifically designed to be bidirectional without the use of a direction pin. The MAX3004-MAX3012 unidirectional level translators level shift data in one direction (VL -> VCC or $V_{CC} \rightarrow V_{L}$) on any single data line. The MAX3000E/MAX3001E/ MAX3002-MAX3012 accept VL from +1.2V to +5.5V. All devices have VCC ranging from +1.65V to +5.5V, making them ideal for data transfer between low-voltage ASICs/PLDs and higher voltage systems.

The MAX3000E/MAX3001E/MAX3002/MAX3004–MAX3012 feature an output enable mode that reduces VCC supply current to less than $2\mu A$, and VL supply current to less than $2\mu A$ when in shutdown. The MAX3000E/MAX3001E have $\pm 15 kV$ ESD protection on the VCC side for greater protection in applications that route signals externally. The MAX3000E operates at a guaranteed data rate of 230kbps; the MAX3001E operates at a guaranteed data rate of 4Mbps and the MAX3002–MAX3012 are guaranteed with a data rate of 20Mbps of operation over the entire specified operating voltage range.

Level Translation

For proper operation, ensure that $+1.65V \le V_{CC} \le +5.5V$, $+1.2V \le V_L \le +5.5V$, and $V_L \le V_{CC}$. During power-up sequencing, $V_L \ge V_{CC}$ does not damage the device. During power-supply sequencing, when V_{CC} is floating and V_L is powering up, up to 10mA current can be sourced to each load on the V_L side, yet the device does not latch up.

The maximum data rate also depends heavily on the load capacitance (see the *Typical Operating Characteristics*), output impedance of the driver, and the operational voltage range (see the *Timing Characteristics* table).

Input Driver Requirements

The MAX3001E/MAX3002–MAX3012 architecture is based on a one-shot accelerator output stage. See Figure 5. Accelerator output stages are always in three-

state except when there is a transition on any of the translators on the input side, either I/O V_L or I/O V_{CC} .

When there is such a transition, the accelerator stages become active, charging (discharging) the capacitances at the I/Os. Due to its bidirectional nature, both stages become active during the one-shot pulse. This can lead to some current feeding into the external source that is driving the translator. However, this behavior helps to speed up the transition on the driven side.

For proper full-speed operation, the output current of a device that drives the inputs of the MAX3000E/MAX3001E/MAX3002–MAX3012 should meet the following requirements:

- MAX3000E (230kbps):
 i > 1mA, R_{drv} < 1kΩ
- MAX3001E (4Mbps):
 i > 10⁷ x V x (C + 10pF)
- MAX3002–MAX3012 (20Mbps):
 i > 10⁸ x V x (C + 10pF)

where i is the driver output current, V is the logic-supply voltage (i.e., V_L or V_{CC}) and C is the parasitic capacitance of the signal line.

Enable Output Mode (EN, EN A/B)

The MAX300E/MAX3001E/MAX3002 and the MAX3004–MAX3012 feature an EN input, and the MAX3003 has an EN A/B input. Pull EN low to set the MAX3000E/MAX3001E/MAX3002/MAX3004–MAX3012s' I/O VCC1 through I/O VCC8 in three-state output mode, while I/O VL1 through I/O VL8 have internal $6k\Omega$ pulldown resistors. Drive EN to logic-high (VL) for normal operation. The MAX3003 is intended for bus multiplexing or bus switching applications. Drive EN A/B low to place channels 1B through 4B in active mode, while channels 1A through 4A are in three-state mode. Drive EN A/B to logic-high (VL) to enable channels 1A through 4A, while channels 1B through 4B remain in three-state mode.

±15kV ESD Protection

As with all Maxim devices, ESD-protection structures are incorporated on all pins to protect against electrostatic discharges encountered during handling and assembly. The I/O V_{CC} lines have extra protection against static discharge. Maxim's engineers have developed state-of-the-art structures to protect these pins against ESD of ±15kV without damage. The ESD structures withstand high ESD in all states: normal operation, three-state output mode, and powered down. After an ESD event, Maxim's E versions keep working without latchup, whereas competing products can latch and must be powered down to remove latchup.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

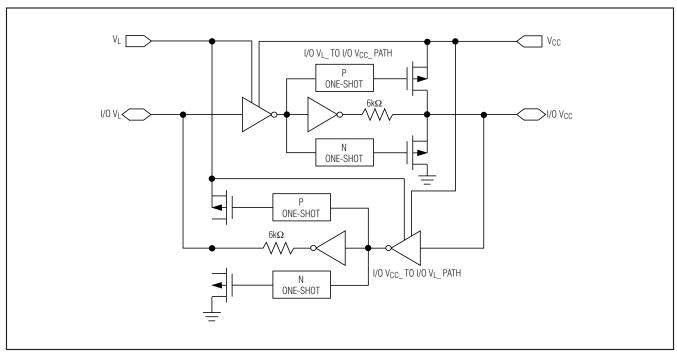


Figure 5. MAX3001E/MAX3002–MAX3012 Simplified Functional Diagram (1 I/O Line)

ESD protection can be tested in various ways. The I/O V_{CC} lines of the MAX3000E/MAX3001E are characterized for protection to $\pm 15 \, \text{kV}$ using the Human Body Model.

ESD Test Conditions

ESD performance depends on a variety of conditions. Contact Maxim for a reliability report that documents test setup, test methodology, and test results.

Human Body Model

Figure 7a shows the Human Body Model and Figure 7b shows the current waveform it generates when discharged into a low impedance. This model consists of a 100pF capacitor charged to the ESD voltage of interest, which is then discharged into the test device through a $1.5 \mathrm{k}\Omega$ resistor.

Machine Model

The Machine Model for ESD tests all pins using a 200pF storage capacitor and zero discharge resistance. Its objective is to emulate the stress caused by contact that occurs with handling and assembly during manufacturing. Of course, all pins require this protection during manufacturing, not just inputs and outputs. Therefore, after PCB assembly, the Machine Model is less relevant to I/O ports.

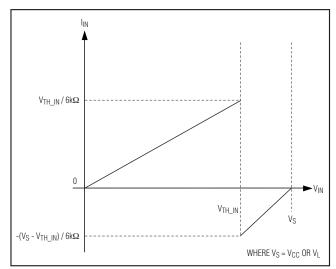


Figure 6. Typical I_{IN} vs. V_{IN}

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Applications Information

Power-Supply Decoupling

To reduce ripple and the chance of transmitting incorrect data, bypass V_L and V_{CC} to ground with a 0.1µF capacitor. To ensure full ± 15 kV ESD protection, bypass V_{CC} to ground with a 1µF capacitor. Place all capacitors as close to the power-supply inputs as possible.

I²C Level Translation

For I²C level translation for I²C applications, please refer to the MAX3372E–MAX3379E/MAX3390E–MAX3393E datasheet.

Unidirectional vs. Bidirectional Level Translator

The MAX3000E/MAX3001E/MAX3002/MAX3003 bidirectional translators can operate as a unidirectional device to translate signals without inversion. The MAX3004–MAX3012 unidirectional level translators, level-shift data in one direction ($V_L \rightarrow V_{CC}$ or $V_{CC} \rightarrow V_L$) on any single data line (see the *Ordering Information*.) These devices provide the smallest solution (UCSP package) for unidirectional level translation without inversion.

+1.2V to +5.5V, $\pm15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

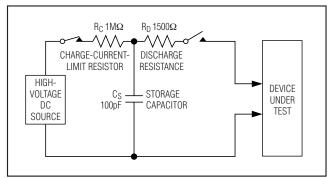


Figure 7a. Human Body ESD Test Model

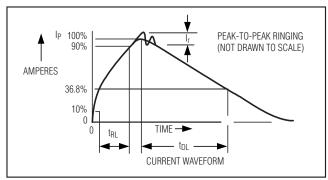


Figure 7b. Human Body Current Waveform

Selector Guide

| PART | EN | EN A/B | Tx/Rx* | DATA RATE | ESD PROTECTION (kV) |
|----------|-----------|--------|--------|-----------|---------------------|
| MAX3000E | √ | _ | 8/8 | 230kbps | ±15 |
| MAX3001E | √ | _ | 8/8 | 4Mbps | ±15 |
| MAX3002 | $\sqrt{}$ | _ | 8/8 | ** | ±2 |
| MAX3003 | _ | √ | 8/8 | ** | ±2 |
| MAX3004 | $\sqrt{}$ | _ | 8/0 | ** | ±2 |
| MAX3005 | $\sqrt{}$ | _ | 7/1 | ** | ±2 |
| MAX3006 | $\sqrt{}$ | _ | 6/2 | ** | ±2 |
| MAX3007 | √ | _ | 5/3 | ** | ±2 |
| MAX3008 | $\sqrt{}$ | _ | 4/4 | ** | ±2 |
| MAX3009 | $\sqrt{}$ | _ | 3/5 | ** | ±2 |
| MAX3010 | √ | _ | 2/6 | ** | ±2 |
| MAX3011 | √ | _ | 1/7 | ** | ±2 |
| MAX3012 | $\sqrt{}$ | _ | 0/8 | ** | ±2 |

 $^{^*}Tx = V_L \rightarrow V_{CC}; Rx = V_{CC} \rightarrow V_L$

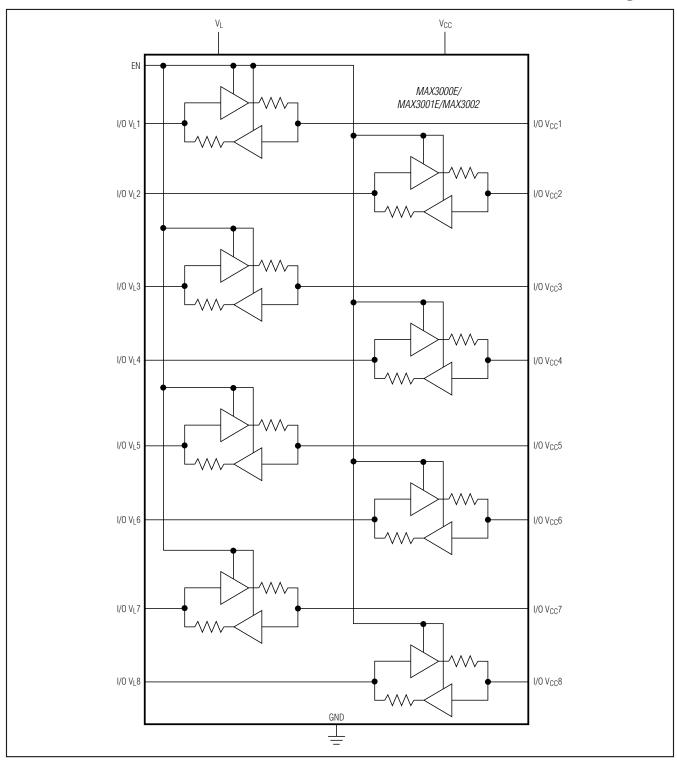
Table 1. Data Rate

| V _L ↔ V _{CC} (V) | MAX3002-MAX3012 GUARANTEED DATA RATE (Mbps) |
|--------------------------------------|---|
| 1.2 ↔ 5.5 | 40 |
| 1.2 ↔ 3.3 | 20 |
| 2.5 ↔ 3.3 | 35 |
| 1.8 ↔ 2.5 | 30 |
| 1.2 ↔ 2.5 | 20 |
| 1.2 ↔ 1.8 | 20 |

^{**}See Table 1.

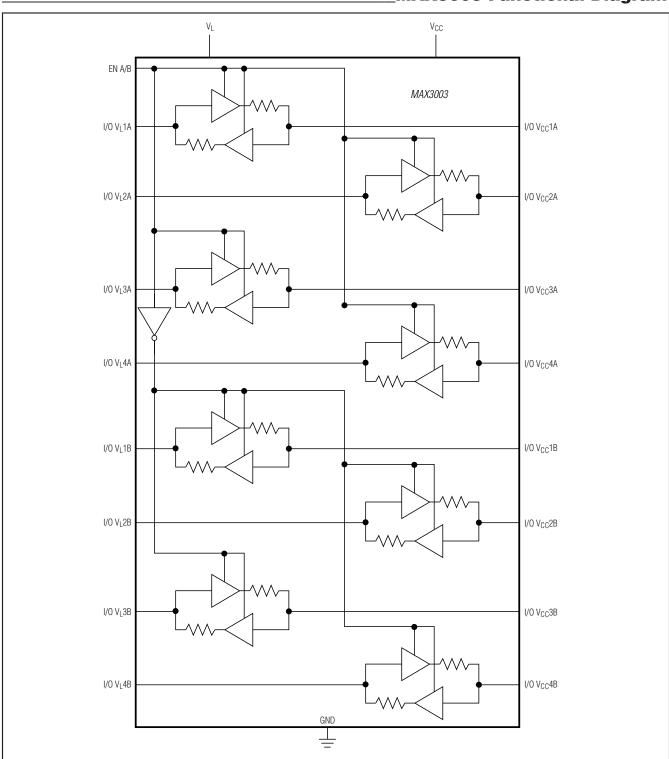
+1.2V to +5.5V, ±15kV ESD-Protected, 0.1µA, 35Mbps, 8-Channel Level Translators

MAX3000E/MAX3001E/MAX3002 Functional Diagram



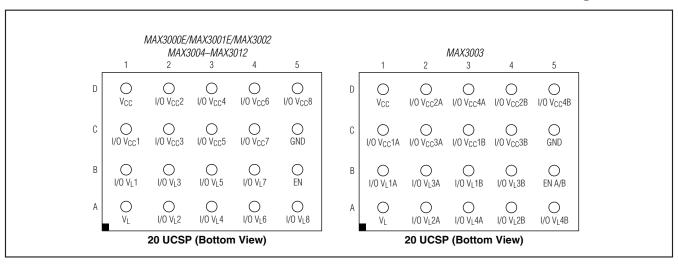
$\pm 1.2 V$ to $\pm 5.5 V$, $\pm 15 kV$ ESD-Protected, $0.1 \mu A$, 35Mbps, 8-Channel Level Translators

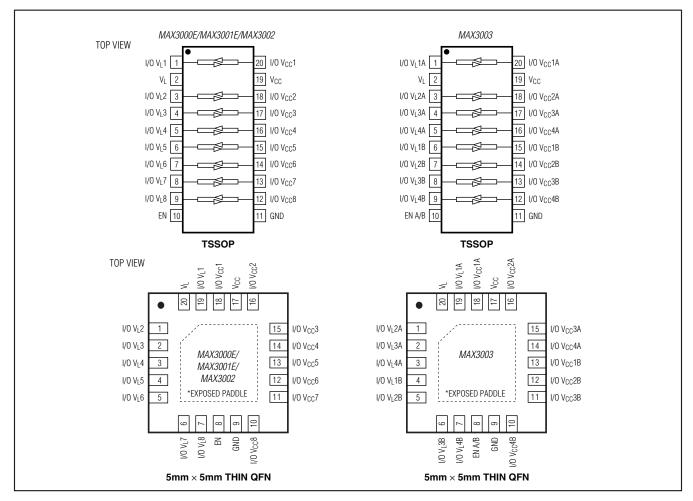
MAX3003 Functional Diagram



+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

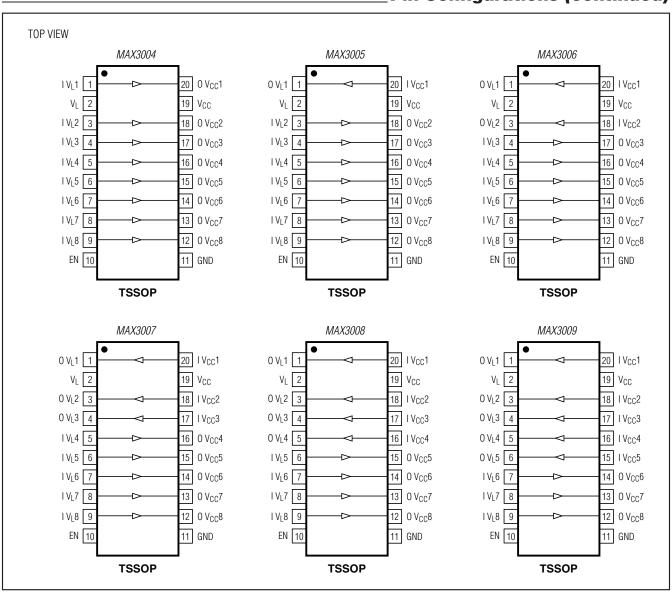
Pin Configurations





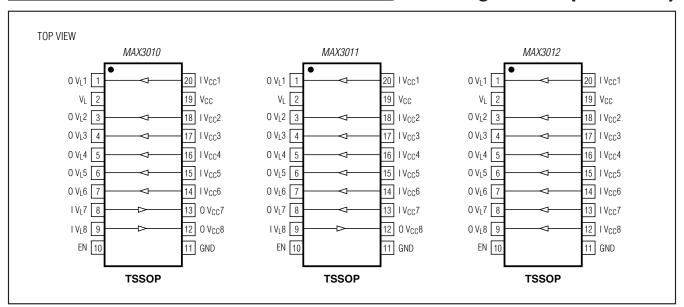
+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Pin Configurations (continued)



+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Pin Configurations (continued)



Ordering Information (continued)

| PART | TEMP RANGE | PIN-PACKAGE | |
|----------------|-----------------|-------------|--|
| MAX3001EEUP | -40°C to +85°C | 20 TSSOP | |
| MAX3001EEBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3001EETP | -40°C to +85°C | 20 TQFN | |
| MAX3001EAUP | -40°C to +125°C | 20 TSSOP | |
| MAX3002EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3002EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3002ETP | -40°C to +85°C | 20 TQFN | |
| MAX3003EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3003EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3003ETP | -40°C to +85°C | 20 TQFN | |
| MAX3004EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3004EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3005EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3005EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3006EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3006EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |

| PART | TEMP RANGE | PIN-PACKAGE | |
|---------------|----------------|-------------|--|
| MAX3007EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3007EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3008EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3008EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3009EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3009EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3010EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3010EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3011EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3011EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |
| MAX3012EUP | -40°C to +85°C | 20 TSSOP | |
| MAX3012EBP-T* | -40°C to +85°C | 4 x 5 UCSP | |

^{*}Future product—contact factory for availability.

_Chip Information

TRANSISTOR COUNT: 1184

PROCESS: BICMOS

⁻T = Tape-and-reel package.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Package Information

For the latest package outline information and land patterns, go to www.maxim-ic.com/packages.

| PACKAGE TYPE | PACKAGE CODE | DOCUMENT NO. | |
|--------------|----------------------|----------------|--|
| 20 TSSOP | U20-3 | <u>21-0066</u> | |
| 20 TQFN | T2055-4 | <u>21-0140</u> | |
| 4 x 5 UCSP | B20-1 21-0095 | | |

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Revision History

| REVISION NUMBER | REVISION DATE | DESCRIPTION | PAGES CHANGED |
|--------------------|------------------|---|---------------------------------------|
| 4 | 12/06 | Added TQFN packages | 1, 2, 3, 10, 11, 15, 16, 21, 23–26 |
| 5 | 8/08 | Changed pin description and package drawing | 1, 10, 11, 23 |



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